



SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known	
				Application Number	09/902,659
				Filing Date	07/12/2001
				First Named Inventor	Kerslick, et al.
				Group Art Unit	3737 2855
				Examiner Name	Not yet assigned. DEN
Sheet	1	of	1	Attorney Docket Number	P789 US

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code			
NO		6,134,300		Trebes, et al.	10-17-2000	
W		2,531,583		Ott, W.	11-28-1950	

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Office Code	Number	Kind				

OTHER DOCUMENTS				
Examiner Initials*	Cite No.	Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

Examiner Signature		Date Considered	2/5/04
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

## INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO.  
P789 US (1737.2110000/LEA)APPLICATION NO.  
09/902,659APPLICANT  
Kerslick et al.FILING DATE  
July 12, 2001GROUP  
323T 2855-

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
AA2						
AB2						
AC2						
AD2						
AE2						
AF2						
AG2						
AH2						
AI2						
AJ2						
AK2	3,688,150	08/1972	Wintzer			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION
AL2						Yes No
AM2						Yes No
AN2						Yes No
AO2						Yes No
AP2						Yes No

## OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

AR	2	Ward, Roger W., "The Constants of Alpha Quartz," 14 <sup>th</sup> Piezoelectric Devices Conference and Exhibition, September 15-17, 1992, Sponsored by Components Group EIA, 1992, (See especially Table I, pp. 3-4)
AS	2	
AT	2	

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
AA3		5,012,102	04/1991	Gowlett			
AB3		6,148,061	11/2000	Shefer et al.			
AC3		6,275,566	08/2001	Smith et al.			
AD3		08/701,764		Chornenky et al.			08/1996
AE3		08/806,244		Chornenky et al.			02/1997
AF3		09/756,287		Chornenky et al.			01/2001
AG3							
AH3							
AI3							
AJ3							
AK3							

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AL3							Yes No
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	APPLICANT Kerslick et al.	
	FILING DATE July 12, 2001	GROUP 328 2855

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
AL	AA1	RE 30,082	08/21/1979	Atlee et al.			
	AB1	3,743,836	07/03/1973	Holland et al.			
	AC1	3,875,028	04/01/1975	Atlee et al.			
	AD1	3,962,583	06/08/1976	Holland et al.			
	AE1	3,979,632	09/07/1976	Gunning et al.			
	AF1	4,288,719	09/08/1981	Hernqvist			
	AG1	4,353,006	10/05/1982	Schade			
	AH1	4,685,118	08/04/1987	Furbee et al.			
	AI1	5,007,074	04/09/1991	Furbee et al.			
	AJ1	5,383,467	01/24/1995	Auer et al.			
W	AK1	5,582,171	12/10/1996	Chornenky et al.			

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AL1						Yes No
	AM1						Yes No
	AN1						Yes No
	AO1						Yes No
	AP1						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
W	AR	1	Chornenky et al., U.S. App. Serial No. 09/760,815, "Miniature X-Ray Device and Method of its Manufacture", Filed: January 17, 2001.
AL	AS	1	Sudarshan et al., "The Effect of Chromium Oxide Coatings on Surface Flashover of Alumina Spacers in Vacuum," IEEE Transactions on Electrical Insulation, Vol, EI-11. No.1, March 1976, pp. 32-35.
W	AT	1	Sudarshan et al., "Prebreakdown Processes Associated with Surface Flashover of Solid Insulators in Vacuum," IEEE Transactions on Electrical Insulation, Vol, EI-12. No.3, June 1977, pp. 200-208.

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>me</i>	AA2	5,713,853	02/03/1998	Clark <i>et al.</i>			
	AB2	5,854,822	12/29/1998	Chornenky <i>et al.</i>			
	AC2	5,904,670	05/18/1999	Schreiner			
	AD2	5,925,016	07/20/1999	Chornenky <i>et al.</i>			
	AE2	6,069,938	05/30/2000	Chornenky <i>et al.</i>			
	AF2	6,095,966	08/01/2000	Chornenky <i>et al.</i>			
	AG2	6,108,402	08/22/2000	Chornenky			
	AH2	6,185,294	02/06/2001	Chornenky <i>et al.</i>			
	AI2	6,280,413	08/28/2001	Clark <i>et al.</i>			
<i>me</i>	AJ2	6,289,079	09/11/2001	Chornenky <i>et al.</i>			
	AK2						

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	AN2						Yes No
	AO2						Yes No
	AP2						Yes No

## OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

<i>me</i>	AR	2	Whetten, N. Ray, "Methods of Experimental Physics" Vol. IV, Section 1.1.4, pp. 69-83 (Academic Press 1962).
	AS	2	
	AT	2	

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*me*

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